## Contents

- ADC
- DAC

**ADC Devices** 

- ADCs (analog-to-digital converters) are among the most widely used devices for data acquisition
  - A physical quantity, like temperature, pressure, humidity, and velocity, etc., is converted to electrical (voltage, current) signals using a device called a *transducer*, or *sensor*
- We need an analog-to-digital converter to translate the analog signals to digital numbers, so microcontroller can read them

ADC804 Chip

## ADC804 IC is an analog-to-digital converter

- It works with +5 volts and has a resolution of 8 bits
- Conversion time is another major factor in judging an ADC
  - Conversion time is defined as the time it takes the ADC to convert the analog input to a digital (binary) number
  - In ADC804 conversion time varies depending on the clocking signals applied to CLK R and CLK IN pins, but it cannot be faster than 110 μs

# TO ADC AND SENSORS

ADC804 Chip (cont') Differential analog inputs where  $V_{in}$ =  $V_{in}$  (+) -  $V_{in}$  (-) Vin (-) is connected

to ground and Vin (+) is used as the analog input to be converted

CS is an active low input used to activate ADC804

+5V power supply or a reference voltage when V<sub>ref</sub>/2 input is open (not connected)

Vin(+) Vcc D0 18 17 16 15 16 15

V<sub>ref</sub>/2

CLKR

CLK in

D GND

RD

"output enable"
a high-to-low RD pulse is
used to get the 8-bit
converted data out of
ADC804

"end of conversion"
When the conversion is
finished, it goes low to signal
the CPU that the converted
data is ready to be picked up

10k

150 pF

"start conversion"
When WR makes a low-to-high transition, ADC804
starts converting the analog input value of V<sub>in</sub> to an 8-bit digital number

#### +5V 10k Vcc Vin(+) POT 18 Vin(-) A GND Vref/2 **LEDs** 19 CLK R 10k D<sub>6</sub> CLK in 150 pF WR 0-5 normally D GND open START

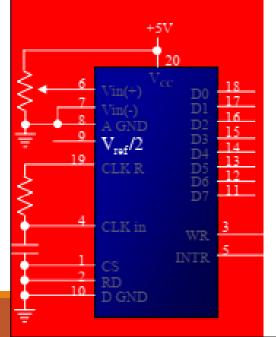
#### CLK IN and CLK R

- CLK IN is an input pin connected to an external clock source
- To use the internal clock generator (also called self-clocking), CLK IN and CLK R pins are connected to a capacitor and a resistor, and the clock frequency is determined by

$$f = \frac{1}{1.1RC}$$

- Typical values are R = 10K ohms and C = 150 pF
- We get f = 606 kHz and the conversion time is 110  $\mu$ s

ADC804 Chip (cont')



## □ Vref/2

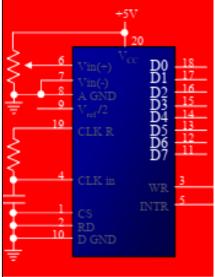
- > It is used for the reference voltage
  - If this pin is open (not connected), the analog input voltage is in the range of 0 to 5 volts (the same as the Vcc pin)
  - If the analog input range needs to be 0 to 4 volts, V<sub>ref</sub>/2 is connected to 2 volts

#### Vref/2 Relation to Vin Range

V <sub>ref</sub> /2(v)	Vin(V)	Step Size ( mV)
Not connected*	0 to 5	5/256=19.53
2.0	0 to 4	4/255=15.62
1.5	0 to 3	3/256=11.71
1.28	0 to 2.56	2.56/256=10
1.0	0 to 2	2/256=7.81
0.5	0 to 1	1/256=3.90

Step size is the smallest change can be discerned by an ADC

ADC804 Chip (cont')



#### D0-D7

- The digital data output pins
- These are tri-state buffered
  - The converted data is accessed only when CS = 0 and RD is forced low
- To calculate the output voltage, use the following formula

$$D_{out} = \frac{V_{in}}{step \ size}$$

- Dout = digital data output (in decimal),
- Vin = analog voltage, and
- step size (resolution) is the smallest change

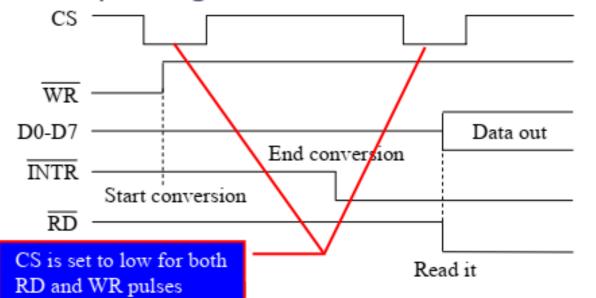
### Analog ground and digital ground

- Analog ground is connected to the ground of the analog V<sub>in</sub>
- ▶ Digital ground is connected to the ground of the V<sub>∞</sub> pin

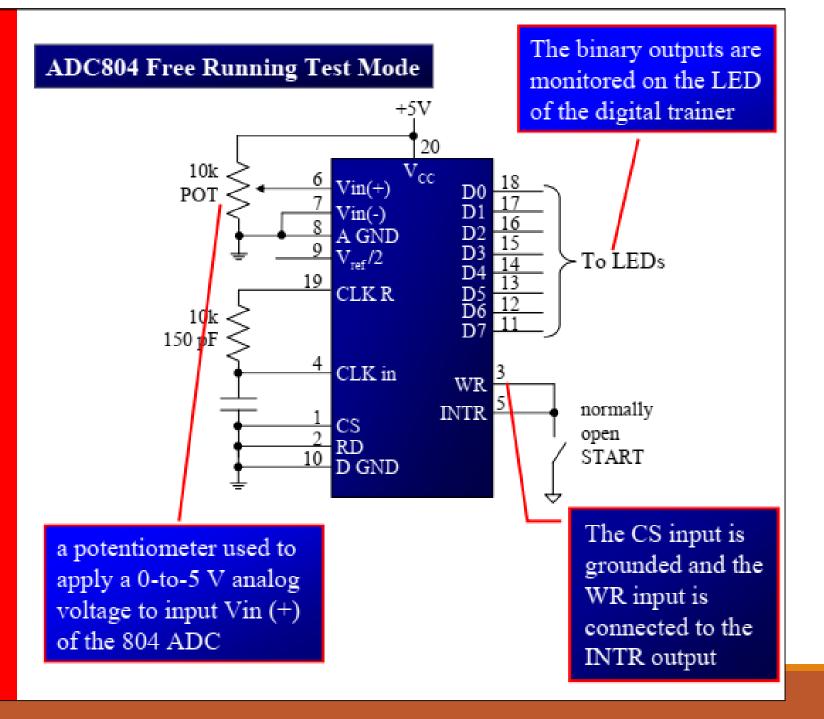
# TO ADC AND SENSORS

ADC804 Chip (cont')

- The following steps must be followed for data conversion by the ADC804 chip
  - Make CS = 0 and send a low-to-high pulse to pin WR to start conversion
  - Keep monitoring the INTR pin
    - If INTR is low, the conversion is finished
    - If the INTR is high, keep polling until it goes low
  - After the INTR has become low, we make CS = 0 and send a high-to-low pulse to the RD pin to get the data out of the ADC804



Testing ADC804



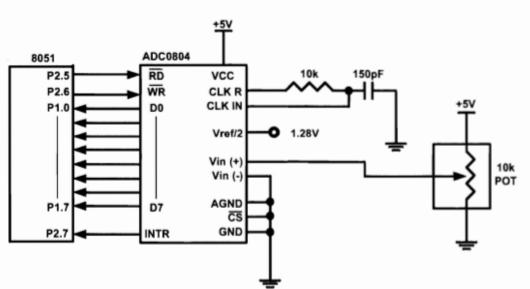
Testing ADC804 (cont')

;p2.7 When low, end-of-conversion) ;p2.5=RD (a H-to-L will read the data from ADC chip) ;p1.0 - P1.7= D0 - D7 of the ADC804 MOV P1, #0FFH ; make Pl = input BACK: CLR P2.6 ; WR = 0SETB P2.6 ;WR = 1 L-to-H to start conversion HERE: JB P2.7, HERE ; wait for end of conversion CLR P2.5 ;conversion finished, enable RD MOV A, P1 ; read the data ACALL CONVERSION ; hex-to-ASCII conversion ACALL DATA DISPLAY; display the data SETB p2.5 ;make RD=l for next round SJMP BACK

Examine the ADC804 connection to the 8051 in Figure 12-7. Write a program to monitor the INTR pin and bring an analog input into register A. Then call a

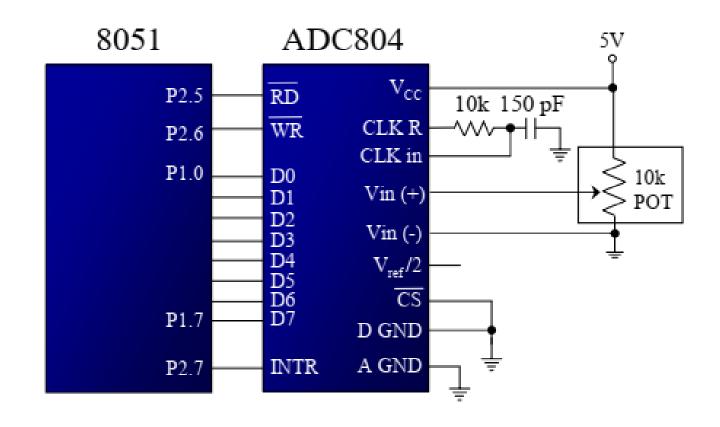
;p2.6=WR (start conversion needs to L-to-H pulse)

hex-to ACSII conversion and data display subroutines. Do this continuously.



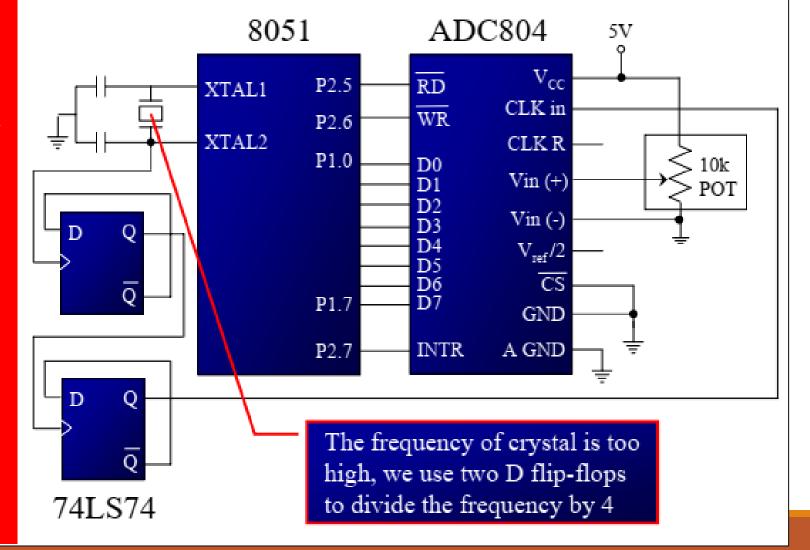
Testing ADC804 (cont')

#### 8051 Connection to ADC804 with Self-Clocking



ADC804 Clock from 8051 XTAL2

#### 8051 Connection to ADC804 with Clock from XTAL2 of 8051



Interfacing Temperature Sensor

- A thermistor responds to temperature change by changing resistance, but its response is not linear
- The complexity associated with writing software for such nonlinear devices has led many manufacturers to market the linear temperature sensor

Temperature (C)	Tf (K ohms)
0	29.490
25	10.000
50	3.893
75	1.700
100	0.817

From William Kleitz, digital Electronics

LM34 and LM35 Temperature Sensors

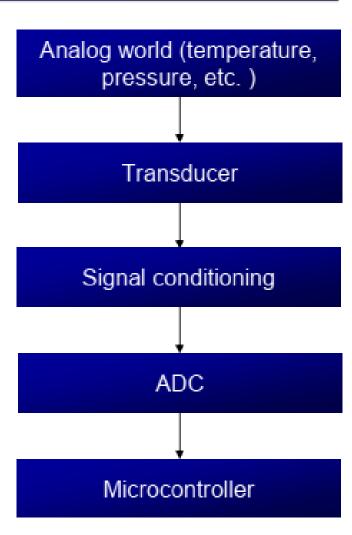
- The sensors of the LM34/LM35 series are precision integrated-circuit temperature sensors whose output voltage is linearly proportional to the Fahrenheit/Celsius temperature
  - ➤ The LM34/LM35 requires no external calibration since it is inherently calibrated
  - It outputs 10 mV for each degree of Fahrenheit/Celsius temperature

Signal
Conditioning
and
Interfacing
LM35

- Signal conditioning is a widely used term in the world of data acquisition
  - ▶ It is the conversion of the signals (voltage, current, charge, capacitance, and resistance) produced by transducers to voltage, which is sent to the input of an A-to-D converter
- Signal conditioning can be a current-tovoltage conversion or a signal amplification
  - The thermistor changes resistance with temperature, while the change of resistance must be translated into voltage in order to be of any use to an ADC

Signal
Conditioning
and
Interfacing
LM35
(cont')

#### Getting Data From the Analog World



Signal Conditioning and Interfacing LM35 (cont')

#### Example:

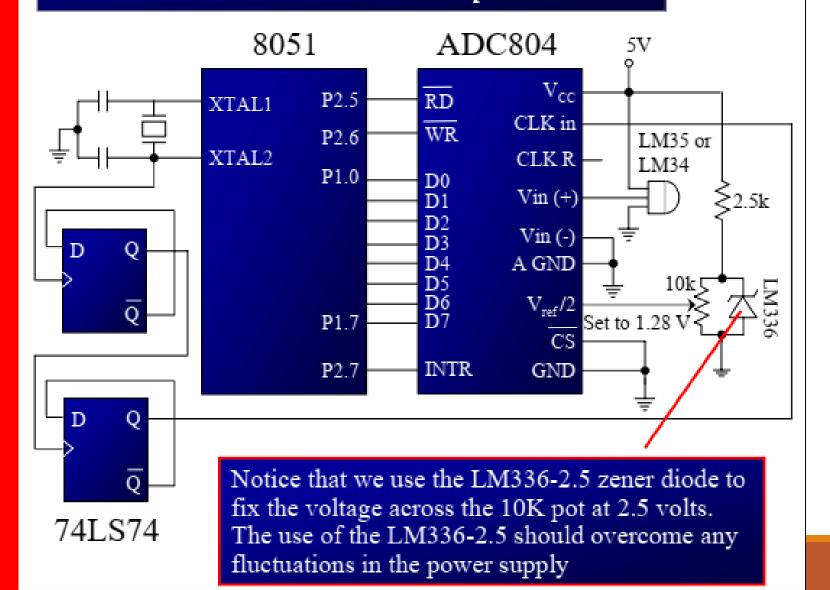
Look at the case of connecting an LM35 to an ADC804. Since the ADC804 has 8-bit resolution with a maximum of 256 steps and the LM35 (or LM34) produces 10 mV for every degree of temperature change, we can condition Vin of the ADC804 to produce a Vout of 2560 mV full-scale output. Therefore, in order to produce the full-scale Vout of 2.56 V for the ADC804, We need to set Vref/2 = 1.28. This makes Vout of the ADC804 correspond directly to the temperature as monitored by the LM35.

#### Temperature vs. Vout of the ADC804

Temp. (C)	Vin (mV)	Vout (D7 – D0)	
0	0	0000 0000	
1	10	0000 0001	
2	20	0000 0010	
3	30	0000 0011	
10	100	0000 1010	
30	300	0001 1110	

Signal
Conditioning
and
Interfacing
LM35
(cont')

#### 8051 Connection to ADC804 and Temperature Sensor



#### Example 13-1

For a given ADC0848, we have  $V_{ref} = 2.56$  V. Calculate the D0 - D7 output if the analog input is: (a) 1.7 V, and (b) 2.1 V.

#### Solution:

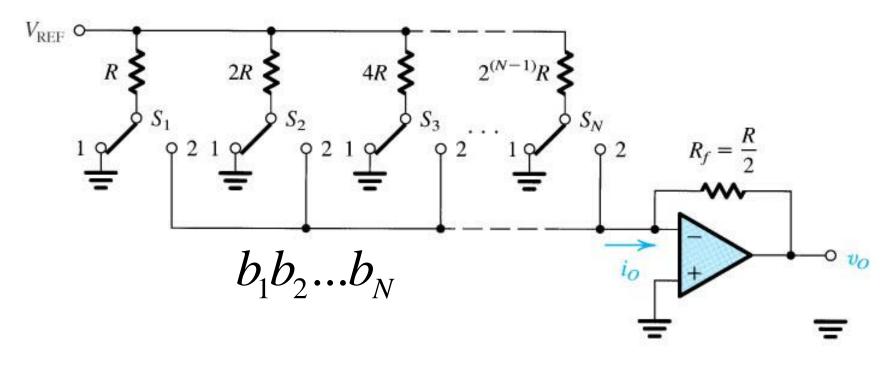
Since the step size is 2.56/256 = 10 mV, we have the following.

- (a)  $D_{out} = 1.7 \text{ V}/10 \text{ mV} = 170 \text{ in decimal, which gives us } 10101011 \text{ in binary for } D7 D0.$
- (b)  $D_{out} = 2.1 \text{ V/}10 \text{ mV} = 210 \text{ in decimal, which gives us } 11010010 \text{ in binary for D7} D0.$

# DAC Interfacing

## **D/A Converter Circuits**

## Binary-weighted registers



$$\left| i_O = \frac{V_{\text{REF}}}{R} b_1 + \frac{V_{\text{REF}}}{2R} b_2 + \dots + \frac{V_{\text{REF}}}{2^{N-1}R} b_N \right|$$

$$v_O = -i_O R_f$$

$$I_{out} = I_{ref} \left( \frac{D7}{2} + \frac{D6}{4} + \frac{D5}{8} + \frac{D4}{16} + \frac{D3}{32} + \frac{D2}{64} + \frac{D1}{128} + \frac{D0}{256} \right)$$

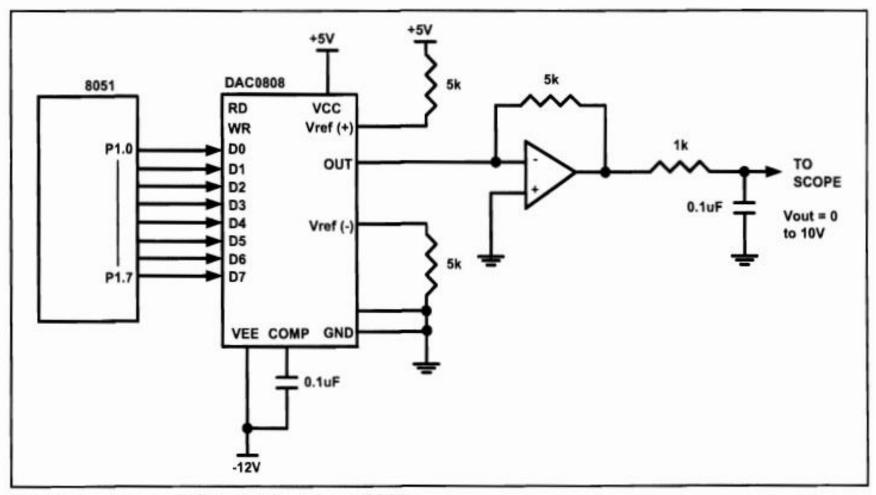


Figure 13-18. 8051 Connection to DAC808

#### **Example:**

In order to generate a stair-step ramp, set up the circuit in Figure 13-18 and connect the output to an oscilloscope. Then write a program to send data to the DAC to generate a stair-step ramp.

#### **Solution:**

AGAIN: MOV P1,A ;send data to DAC INC A ;count from 0 to FFH ACALL DELAY ;let DAC recover SJMP AGAIN

**Table: Angle vs. Voltage Magnitude for Sine Wave** 

Angle θ (degrees)	Sin θ	$V_{out}$ (Voltage Magnitude) 5 V + (5 V × sin $\theta$ )	Values Sent to DAC (decimal (Voltage Mag. × 25.6)
0	0	5	128
30	0.5	7.5	192
60	0.866	9.33	238
90	1.0	10	255
120	0.866	9.33	238
150	0.5	7.5	192
180	0	5	128
210	-0.5	2.5	64
240	-0.866	0.669	17
270	-1.0	0	0
300	-0.866	0.669	17
330	-0.5	2.5	64
360	0	5	128

#### Example 13-5

Verify the values given for the following angles: (a) 30° (b) 60°.

#### **Solution:**

- (a)  $V_{out} = 5 \text{ V} + (5 \text{ V} \times \sin q) = 5 \text{ V} + 5 \times \sin 30^{\circ} = 5 \text{ V} + 5 \times 0.5 = 7.5 \text{ V}$ DAC input values = 7.5 V x 25.6 = 192 (decimal)
- (b)  $V_{out} = 5 \text{ V} + (5 \text{ V} \times \sin q) = 5 \text{ V} + 5 \times \sin 60^{\circ} = 5 \text{ V} + 5 \times 0.866 = 9.33 \text{ V}$ DAC input values = 9.33 V x 25.6 = 238 (decimal)

#### Figure: Angle vs. Voltage Magnitude for Sine Wave

AGAIN: MOV DPTR, #TABLE

MOV R2, #COUNT

BACK: CLR A

MOVC A,@A+DPTR

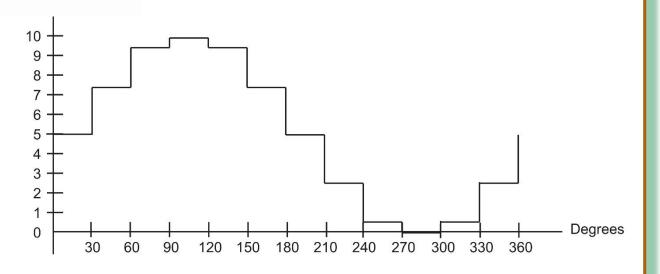
MOV P1,A INC DPTR

DJNZ R2,BACK SJMP AGAIN

ORG 300

TABLE: DB 128,192,238,255,238,192 ;see Table 13-7

DB 128,64,17,0,17,64,128



## **Thank You**